


<b>Search Notes</b> 	<b>Application/Control No.</b> 10702449	<b>Applicant(s)/Patent Under Reexamination</b> MORISHITA, TAKUYA
	<b>Examiner</b> Werner, David N	<b>Art Unit</b> 2621

SEARCHED			
Class	Subclass	Date	Examiner
386	52, 53, 98	5/29/2007	DNW
375	240.13	5/30/2007	DNW
386	55	6/1/2007	DNW
386	52, 53	10/31/2007	DNW

SEARCH NOTES		
Search Notes	Date	Examiner
EAST	5/29/2007	DNW
Esp@cenet	5/29/2007	DNW
E-mail to Thai Tran regarding allowability	6/1/2007	DNW
Double-Patent check	6/4/2007	DNW
EAST	10/31/2007	DNW
Espacenet	11/1/2007	DNW
Espacenet, ISR for W0 01/35411 A1 (same as cited Lin et al. reference) searched	5/5/2008	DNW
IEEE Xplore	5/5/2008	DNW
Interference search	8/19/2008	DNW
Edan double patent check	8/19/2008	DNW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
386	52-54, 98	8/19/2008	DNW

/D. N. W./  
Examiner, Art Unit 2621